



# **Positron studies in self-irradiated tungsten**

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#### Fusion a new challenge for energy production



#### Inner poloidal field coils TOKAMAK (primary transformer circuit) Outer poloidal field coils Poloidal magnetic field (for plasma positioning and shaping) 1rst concept in the 1950s by Soviet physicists Igor Tamm and Andrei Sakharov, inspired by a letter by Oleg Lavrentiev **Fusion reaction** $^{2}H + ^{3}H \rightarrow ^{4}He(3,5 \text{ MeV}) + n (14.1 \text{ MeV})$ [1] Hydrogen Plasma roidal field coils $10 \text{ keV over } 100 \times 10^6 \text{C}^\circ\text{(} > \text{sun } -25 \times 10^6 \text{°C}\text{)}$ Resulting helical magnetic field Magnetic Toroidal magnetic field Plasma electric current (secondary transformer circuit) confinement Short-term Medium-term Long-term Fusion Power Plants ITER 50 operating tokamaks in the world [2] [3] ✓ ITER, DEMO : steps in the development of fusion energy production **ITER Tokamak**

[1] S. Li, H. Jiang, Z. Ren, C. Xu - S. Li et. al., Abstract and Applied Analysis doi:10.1155/2014/940965, CC BY 4.0, https://commons.wikimedia.org/w/index.php?curid=74679708, [2] http://www.tokamak.info/,; [3] A.J.H. Donné | SOFT, Sicily, IT | 17 September 2018







✓ ITER, DEMO : very hard conditions for materials



Big challenges : for thermal, electrical and mechanical properties

Tungsten divertor (ITER), first walls? (DEMO)







CDEFGHIJKLMN

#### **Calculations in DEMO**



#### W for FW or divertor

Damage dose max in 3 years = 12dpa [He]max in 3 years = 20-30 appm He/damage = 1.6-2.5 appm/dpa



• Large energy distribution (up to 1 MeV) mean value at 150 keV



[1] M.R. Gilbert et al. / JNM 442 (2013) S755–S760, M.R. Gilbert et al. / JNM 467 (2015) 121



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[1] A. Hasegawa et al. / Fusion Engineering and Design 89 (2014) 1568–157, [2] A. Barabash et al. / Journal of Nuclear Materials 283–287, (2000) 138-146. [3] M. R. Gilbert et al / (2013). Journal of Nuclear Materials 442, (2013) \$755-\$760









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Self irradiations : W (150-2 MeV) ions

#### Dislocation loops: ½<111>, <100>



2 MeV W, 0.4 dpa, 500°C [1] : Loops ½<111> : 3.3 x10<sup>22</sup> m<sup>-3</sup> mean size 3-4 nm [1]

 ✓ For irradiation at 500°C, preferential formation of <100> loops at low dpa

[1] X Yi et al Acta Materialia 92 (2015) 163–177





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# ✓ Objective : Vacancy defects?

Quantitative data with the best precision to be shared with modeling

> Experimental investigations of damage induced by ion irradiations

- Effect of damage dose
- Effect of temperature
- Role of impurities

Development of a characterization methodology

• combine characterization techniques PAS and TEM





#### **DB-PAS results: virgin sample**







#### Virgin sample

- $\Box$  L<sub>eff</sub><sup>+</sup>=~100nm
- Lifetime : 105-108 ps = lattice theoretical value 101 [1] -108[2] ps

Detection limit DB-PAS  $\Box$  C<sub>V</sub><10<sup>5</sup> µm<sup>-3</sup>

 $S_L = 0.367(4), W_L = 0.084(5))$ 

[1] A. Yabuuchi, M. Tanaka and A. Kinomura / Journal of Nuclear Materials 542 (2020) 152473.[2] T. Troev, E. Popov, et al, NIMB 267, (2009), 335

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[1] A Debelle , MF Barthe et al, JNM.376 (2008) 216; [2] T. Troev, E. Popov, et al, NIMB 267, (2009), 335; [3] P.E. Lhuillier, MF Barthe et al., *PSS , C6, (2009), 2329,* [4] C.Becquart, et al JNM 403, Issues 1-3, 2010, 75-88



# After annealing Single vacancy → V-clusters in W





[1] A Debelle, MF Barthe et al, JNM.376 (2008) 216; [2] T. Troev, E. Popov, et al, NIMB 267, (2009), 335; [3] P.E. Lhuillier, MF Barthe et al., PSS, C6, (2009), 2329, [4] C.Becquart, et al JNM 403, Issues 1-3, 2010, 75-88



Cemht





## **New studies**

# Self irradiation damage







Before irradiation : Annealing at 1600°C/1H/Vacuum

#### Irradiation with W ions, SRIM calculations (KP)

- **1.2 MeV** in thin and thick samples:
- 2 or 20 MeV in thick samples:





#### Slow positron beam









# Self irradiation damage ✓ At low dpa and low temperature







1.2 MeV W







#### TEM (0.02 dpa\*, RT)

#### In thin lamella irradiated with 1.2 MeV W



#### → Vacancy clusters are generated in the cascades

[1] N=(d/(2xr<sub>w</sub>))<sup>3</sup>
 [2]A. Sand et al JNM 455 (2014) 207–211
 [3] M. W. Thompson, Philosophical Magazine, (1960) 5:51, 278-296, [4] C.Becquart, et al JNM 403, Issues 1-3, 2010, 75-88







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#### → single vacancies and vacancy clusters are generated in the cascades

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 [2]A. Sand et al JNM 455 (2014) 207–211
 [3] M. W. Thompson, Philosophical Magazine, (1960) 5:51, 278-296, [4] C.Becquart, et al JNM 403, Issues 1-3, 2010, 75-88

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#### **1.2 MeV W in situ irradiation at RT + PAS-DB**









# Self irradiation damage ✓ At low dpa and low temperature ✓ As a function of dpa at RT







In 2 MeV self-irradiated W at RT



- ✓ From 0.0085- 1.7 dpa
- ✓ S increases W decreases
- 2 damaged layers close to the SRIM depth profile







#### 2 MeV W irradiation : Effect of the fluence







|         |                             |          | Damage dose (dpa) |          |          |          |  |
|---------|-----------------------------|----------|-------------------|----------|----------|----------|--|
|         |                             | 0.0085   | 0.085             | 0.425    | 0.85     | 1.7      |  |
| Surface | S <sub>Surf</sub>           | 0.419(1) | 0.430(1)          | 0.432(1) | 0.431(1) | 0.431(1) |  |
|         | W <sub>Surf</sub>           | 0.057(1) | 0.054(1)          | 0.053(1) | 0.054(1) | 0.054(1) |  |
| Layer 1 | S <sub>Lav</sub>            | 0.418(1) | 0.432(1)          | 0.438(1) | 0.440(1) | 0.440(1) |  |
|         | W <sub>Lay</sub>            | 0.058(1) | 0.053(1)          | 0.051(1) | 0.050(1) | 0.050(1) |  |
|         | $(S_{Lay}S_L)/(W_{Lay}W_L)$ | 1.96(4)  | 2.10(4)           | 2.15(4)  | 2.15(4)  | 2.15(4)  |  |
|         | L <sup>+</sup> Lav (nm)     | 14(4)    | 4-6               | 4-5      | 5-7      | 5-7      |  |
|         | Thickness (nm)              | 100(5)   | 90(5)             | 110(10)  | 120-170  | 120-170  |  |
| Layer 2 | S <sub>Lav</sub>            | 0.402(1) | 0.417(1)          | 0.425(1) | 0.428(5) | 0.428(5) |  |
|         | W <sub>Lav</sub>            | 0.067(1) | 0.059(1)          | 0.057(1) | 0.054(2) | 0.054(2) |  |
|         | $L^+_{Lav(nm)}$             | 60       | 50                | 45       | 30       | 30       |  |
|         | Thickness (nm)              | 510(10)  | 510(20)           | 570(10)  | 610(45)  | 610(45)  |  |

- Thickness of the first damaged layer : 100 nm as maximum in SRIM
- For 0- 0.425 dpa,
  - S<sub>Lay1</sub> increases and W<sub>Lay1</sub> decreases
  - Effective diffusion length  $L^+_{Lay1}$  decreases  $\rightarrow$  density of traps increases
  - The slope  $(S_{lay}-S_L)/(W_{Lay}-W_L)$  increases with dpa  $\rightarrow$  vacancy clusters fraction increases
- $\blacktriangleright$  From 0.85 dpa, S<sub>Lay1</sub>, W<sub>Lay1</sub> and L<sup>+</sup><sub>Lay1</sub> remain constant



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#### PAS : RT, DBS /SPB



|    | Damage (dpa) | L <sup>+</sup> <sub>Lay1</sub> (nm) | $C_V^{tot}$ (m <sup>-3</sup> ) | Fraction of atomic density |
|----|--------------|-------------------------------------|--------------------------------|----------------------------|
| -> | 0.0085       | $14 \pm 4$                          | 9.2x10 <sup>25</sup>           | 0.0015                     |
|    | 0.085        | 5                                   | $> 1.1 \times 10^{27}$         | > 0.018                    |

for tungsten  $D^+ = 1.26 \times 10^{-4} \text{ m}^2/\text{s} [1]$   $\lambda_L = 1/\tau_L, \tau_L = 101-105 \text{ ps} [1]$  $\mu_V = 6 \pm 3 \times 10^{-15} \text{ cm}^3.\text{s}^{-1} [1]$ 

[1] A. Hollingsworth, MF Barthe et al to be published in JNM

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DBS: Doppler broadening Spectroscopy SPB : Slow Positron Beam



















# Self irradiation damage At low dpa and low temperature As a function of dpa RT After annealing as a function of dpa









For all dpa levels 3 annealing stages

[1] M Sidibe PhD thesis Orleans University 2014

















**Defects distribution is equivalent for dpa level** > **or** = **1 dpa** 

- For all dpa levels 3 annealing stages
  - S increase and W decrease
  - $|(S-S_i)/(W-W_i)|$  increases

→ agglomeration to form large Vacancy clusters

- Damage recovery
- For low dpa (0.03 and 0.06 dpa)
  - $(S-S_l)/(W-W_l)$  and size of vacancy clusters increases when damage dose increases
- For high dpa (1 and 12 dpa)
  - No differences for 1 and 12 dpa  $\geq$
- $\succ$  S<sub>Max</sub>, W<sub>min</sub>  $\rightarrow$  New annihilation State ?









#### <sup>3</sup>He 800 keV irradiation (5x10<sup>16</sup> cm<sup>-2</sup>) and annealing





[1] P E Lhuillier et al Phys. Status Solidi C 6, No. 11, 2329–2332 (2009) / DOI 10.1002/pssc.200982114







# Self irradiation damage

At low dpa and low temperature
 As a function of dpa at RT
 Role of purity



# **Cembtr** Role of impurities on the irradiation induced damage microstructure



#### Source of impurities

- ≻ H, He from Plasma and transmutations<sup>[2]</sup>
- → bubbles, fuzz...
- ≻ Transmutation elements (Re, Os, Ta..) <sup>[3]</sup>
  - → precipitates...
- Reactor's environment light elements <u>impurities (C, N, O...)</u><sup>[4-5]</sup>
  - Impurity-defects complexes



Loops density and size as a function of dpa OKMC (Object Kinetic Monte Carlo) simulations [1]



(Start of the assembly on <u>28 July 2020</u>)

[1] N. Castin, et al J. Nucl. Mater. 527 (2019); 1 . Hirai, T. et al.. Nuclear Materials and Energy 9, 616–622 (2016). 2 Greenwood.al 212–215, 635–639 (1994). 3 *Computational Materials Science* 184, 109932 (2020). 3 Liu. Computational Materials Science 50, 3213–3217 (2011). 4 You, Y.-W. et al.. RSC Adv. 5, 23261–23270 (2015). 5 Alkhamees, A. et al.. Journal of Nuclear Materials 393, 508–512 (2009).

 $^{2}H + ^{3}H \rightarrow ^{4}He(3.5MeV) + ^{1}n(14.1MeV)$ 



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  - → precipitates...
- ➢ Reactor's environment light elements <u>impurities (C, N, O...) or LEs [4-5]</u>
  - → Impurity-defects complexes

Vacancy interactions with LEs DFT calculations

| X | $E_m^X$ (eV)        |           | $     \begin{bmatrix}             F_{diss}^{V-X_1} \\             (eV)             $ |
|---|---------------------|-----------|--|
| Н | 0.21 (TIS-TIS) [24] | 1.24 [25] | 1.45   |
| С | 1.46 (TIS-OIS) [20] | 1.93 [20] | 3.39   |
| Ν | 0.73 (TIS-OIS) [26] | 2.48 [21] | 3.21   |
| 0 | 0.17 (TIS-TIS) [22] | 3.05 [22] | 3.22   |

 $^{2}H + ^{3}H \rightarrow ^{4}He(3.5MeV) + ^{1}n(14.1MeV)$ 





Light element *impurities* (H,C,N,O )

- **defects**(single vacancy, vacancy-complexes and SIA).

[1] N. Castin, et al J. Nucl. Mater. 527 (2019); 1. Hirai, T. et al.. Nuclear Materials and Energy 9, 616–622 (2016). 2 Greenwood.al 212–215, 635–639 (1994). 3 *Computational Materials Science* 184, 109932 (2020). 3 Liu. Computational Materials Science 50, 3213–3217 (2011). 4 You, Y.-W. et al.. RSC Adv. 5, 23261–23270 (2015). 5 Alkhamees, A. et al.. Journal of Nuclear Materials 393, 508–512 (2009). 6 A. Vehanen et al Phys Rev B 25 (1982) 762







#### Polycristalline W : 2 purities : 6N-XHP and 3N-HP



Dpa\* : mean dpa value in **700nm** surface region,



Z. Hu, MF Barthe et al , Journal of Nuclear Materials 556 (2021) 153175







1.2 MeV W 0.02dpa 500°C



JEOL ARM200F cold field emission gun microscope and Over-focus (+300 nm) images

Z. Hu, MF Barthe et al , Journal of Nuclear Materials 556 (2021) 153175









Larger cavities in 6N-XHP samples

| compare to 3N-HP             |       |
|------------------------------|-------|
| Damage level (dpa)           |       |
|                              |       |
| Irradiation Temperature (°C) |       |
| Purity                       | 3N-HP |
|                              |       |

| Damage level (dpa)                          | 0.02            |                 |                 |                 |  |  |  |
|---|-----------------|-----------------|-----------------|-----------------|--|--|--|
|   |                 |                 |                 |                 |  |  |  |
| adiation Temperature (°C)                   | 500             |                 | 700             | )               |  |  |  |
| Purity                                      | 3N-HP           | 6N-XHP          | 3N-HP           | 6N-XHP          |  |  |  |
| Thickness (nm)                              | 55 ± 20         | 90 ± 30         | 35 ± 20         | 60 ± 50         |  |  |  |
| Thickness (htt)                             | (EFTEM)         | (EFTEM)         | (evaluated)     | (evaluated)     |  |  |  |
| Mean diameter(nm)                           | 0.97 ± 0.19     | 1.13 ± 0.21     | 0.97 ± 0.25     | 1.22 ± 0.25     |  |  |  |
| Density (10 <sup>24</sup> m <sup>-3</sup> ) | $1.73 \pm 0.71$ | $1.56 \pm 0.52$ | $0.70 \pm 0.42$ | 0.60 ± 0.53     |  |  |  |
| Swelling %                                  | $0.09 \pm 0.02$ | $0.12 \pm 0.04$ | $0.04 \pm 0.02$ | $0.08 \pm 0.05$ |  |  |  |
|   |                 |                 |                 |                 |  |  |  |

Z. Hu, MF Barthe et al , Journal of Nuclear Materials 556 (2021) 153175





M. F. Barthe, PSD-18, Mumbai on line 1-5/03/2021

6N-XHP

60 ± 50

(evaluated)

1.22 ± 0.25

 $0.60 \pm 0.53$ 

 $0.08 \pm 0.05$ 

700

CINIS

 $\tau_{Vn} = 440 \text{ ps}$ 

**TEM in 0.02 dpa 500°C** 





- Larger cavities in 6N-XHP samples compare to 3N-HP
- ➢ as in PAS
- D<sub>3</sub> line : trapping competition in large vacancy clusters V<sub>N</sub> and an unknown trap **T**?, |(S<sub>Max</sub>-S<sub>T</sub>)/(W<sub>min</sub>-W<sub>T</sub>)|≈ 3.5
- T? annihilation characteristics on
   D<sub>3</sub> line





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| Sample      | Purity<br>%wt | Damage<br>level(dpa) | Temperature<br>°C | S         | W         | L <sup>+</sup> <sub>eff</sub><br>(nm) |   |
|-------------|---------------|----------------------|-------------------|-----------|-----------|---------------------------------------|---|
| G-35        | 99.95         | 0                    | -                 | 0.369(2)  | 0.0828(4) | 132(6)                                | Close to Lattice values, very low   |
| J-17        | 99.9999       | 0                    | -                 | 0.369(2)  | 0.0834(4) | 105(4)                                | concentration of defects  |
| G-04        | 99.95         | 0.01                 | DT                | 0.417 (2) | 0.0599(6) | 0.9(3)                                |   |
| J-05        | 99.9999       | 0.01                 | KI                | 0.417(2)  | 0.0590(9) | 0.7(2)                                | Single vacancy as the main vacancy defects  |
| G-05        | 99.95         |                      |                   | 0.459(2)  | 0.0483(9) | 15(2)                                 |   |
| J-11        |               | 0.02                 | 500               | 0.473(4)  | 0.0429(8) | 9(1)                                  | No difference in effective diffusion length for   |
| <b>J-06</b> | 99.9999       | 0.02                 | 500               | 0.474 (3) | 0.043 (1) | 12(2)                                 | both purifies and both irradiation  |
| J-15        |               |                      |                   | 0.473(4)  | 0.044 (1) | 12(2)                                 | $\sim$ temperatures   |
| G-02        | 99.95         | 0.02                 | 700               | 0.456(4)  | 0.051(1)  | 14(2)                                 | $ \stackrel{\text{L}}{\rightarrow} A \text{ high total transing rate } K \sim 8 \times 10^{11} \text{ s}^{-1} $ |
| <b>J-03</b> | 99.9999       | 0.02                 | 700               | 0.469(7)  | 0.0461(9) | 17(2)                                 | $\gamma A$ high total trapping rate $R_{tot} \sim 0 \times 10^{-5}$   |
|             |               |                      |                   |           |           |                                       | $\bigstar K_{tot} \approx K_{cav} + K_{T}$  |

For 500°C

$$K_{cav} = 3 \times 10^{11} \text{ s}^{-1}$$
. using  $\mu_{cav} = 1.6 \times 10^{-13} \text{ m}^3 \text{ s}^{-1} [1]$ 

→  $K_{T_{=}} 5 \times 10^{11} \text{ s}^{-1}$ . =  $C_T \times \mu_T$  if  $\mu_T = \mu_V = 6 \pm 3 \times 10^{-15} \text{ m}^{-3}$ .s<sup>-1</sup> [1] →  $C_T \approx 7 \times 10^{25} \text{ m}^{-3}$  (i.e. about 1200 at. ppm).







For lower C concentration

Larger cavities in 6N-XHP samples compare to 3N-HP

As in carbon doped iron [6]

- $\rightarrow$  Higher concentration of V in V<sub>N</sub> clusters
  - → Carbon trapping at V prevent agglomeration
- $\rightarrow$  Lower concentration V-C complexes









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 $\rightarrow$  Higher concentration of V in V<sub>N</sub> clusters

→ Carbon trapping at V prevent agglomeration

 $\rightarrow$  Lower concentration V-C complexes

|          | Irradiation at 500° |         |        |                     |                   |             |  |  |
|----------|---------------------|---------|--------|---------------------|-------------------|-------------|--|--|
|          | V                   | at. ppm |        | EX                  | $E_{1}^{V-X_{1}}$ | $E^{V-X_1}$ |  |  |
| <b>.</b> | Λ                   | 3N-HP   | 6N-XHP | (eV)                | (eV)              | (eV)        |  |  |
| IN W     | ×                   | 910     | Ud     | 0.21 (TIS-TIS) [24] | 1.24 [25]         | 1.5         |  |  |
|          | С                   | 460     | Ud     | 1.46 (TIS-OIS) [20] | 1.93 [20]         | 3.39        |  |  |
|          | Ν                   | 130     | Ud     | 0.73 (TIS-OIS) [26] | 2.48 [21]         | 3.21        |  |  |
|          | 0                   | 345     | Ud     | 0.17 (TIS-TIS) [22] | 3.05 [22]         | 3.22        |  |  |
|          |                     | -       |        |                     | L J               |             |  |  |

T? = vacancy complexes with C,O, N

[1] N. Castin, et al J. Nucl. Mater. 527 (2019); 1. Hirai, T. et al.. Nuclear Materials and Energy 9, 616–622 (2016). 2 Greenwood.al 212–215, 635–639 (1994). 3 *Computational Materials Science* 184, 109932 (2020). 3 Liu. Computational Materials Science 50, 3213–3217 (2011). 4 You, Y.-W. et al.. RSC Adv. 5, 23261–23270 (2015). 5 Alkhamees, A. et al.. Journal of Nuclear Materials 393, 508–512 (2009). 6 A. Vehanen et al Phys Rev B 25 (1982) 762







TEM / PAS (slow positron beams + lifetime and Doppler) complementary techniques to characterize vacancy defects from single to clusters

→ PAS more adapted for single vacancy or small size complexes detection

- Self Damage
  - ✓ In RT W irradiated W : small vacancy clusters (TEM) + a majority of single vacancies (PAS)
    - $\checkmark\,$  Saturation of S and W characteristics
    - $\checkmark\,$  Annealing leads to agglomeration f vacancies to form large vacancy clusters

➔ damage saturation when damage dose >0.5 dpa as in modeling due to point defect recombination and cascade overlaping

- ✓ In 500°C W irradiated W :
  - ✓ Cavities distribution depends on W purity
  - ✓ Larger vacancy clusters (PAS and TEM) for 6N-XHP
  - ✓ A new trap T?

→ T = V-Imp (C, O, N)

Perspectives : DFT calculations in collaboration with KTH (SW) SIMS annalysis







# Thank you for your attention

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